

57th ARFTG Conference Schedule

“Best Practice and Strategies for RF Test”

- 7:00 AM – 8:00 AM Breakfast
- 8:00 AM – 10:00 AM Technical Session 1—On-Wafer Measurement
- 8:00 AM Welcome
- 8:10 AM (Invited) “High-Throughput Microwave Probing” *Eric Strid (Cascade Microtech)*
- 8:55 AM “Best Practice for On-Wafer Millimeter Wave Noise Figure Measurements” *A. Rodriguez, L. Dunleavy, and P. Kirby (University of South Florida)*
- 9:20 AM “Direct Characterization of Non-Insertable Microwave Test Fixtures for Packaged MMICs” *J. King and B. Biron (M/A-COM)*
- 9:45 AM Introduction—Exhibitors and Interactive Presentations
- 10:00 AM – 11:00 AM Exhibition/Interactive Session
- 11:00 AM – 12:00 Noon Technical Session 2—Production Testing
- 11:00 AM (Invited) “Practical Test Considerations in a Production Microwave Component Manufactory” *John Mahon (M/A-COM)*
- 11:45 AM “Optimum phase noise measurements for every application” *D. Köther, J. Berben, W. Poppelreuter, P. Waldow (IMST GmbH)*
- 12:10 PM – 1:30 PM Luncheon
- 1:30 PM – 3:00 PM Technical Session 3—Optical & Nonlinear Meas.
- 1:30 PM (Invited) “Lightwave S-parameter Measurement Techniques” *Stavros Iezekiel (University of Leeds)*
- 2:15 PM “Large-Signal Time-Domain Characterization of Microwave Transistors Under RF Pulsed Conditions” *J.P. Teyssier, S. Augaudy, D. Barataud, J-M. Nébus, R. Quéré (Université de Limoge)*
- 2:40 PM “Comparison of Active and Passive Load-Pull Benches” *C. Arnaud, J-L Carbonero, J-M Nébus (STMicroelectronics)*
- 3:00 PM – 4:00 PM Exhibition/Interactive Session
- 4:00 PM – 5:00 PM Technical Session 4—Characterization
- 4:00 PM “Separation of the Nonlinear Source-Pull from the Nonlinear System Behavior” *P. Crama, Y. Rolain, W. Van Moer, J. Shoukens (Vrije Universiteit Brussel)*
- 4:25 PM “A CPW T-Resonator Technique for Electrical Characterization of Microwave Substrates” *R. Peterson, R. Drayton (Princeton University)*
- 5:00 PM Adjourn

Interactive Session Presentations

"A Novel Technique for the Dynamic Characterisation of Non-Linear Effects in RF Power Amplifiers" *S. Cripps (Hywave Associates)*

"An RF/DSP Test Bed for Baseband Pre-Distortion of RF Power Amplifiers" *W. Woo, L. Ding, J.S. Kenney, G.T. Zhou (Georgia Tech.)*

"In-circuit, Non-Contacting, S-parameter measurement for planar circuits." *J. Stenarson, K. Yhland, C. Wingqvist (Chalmers University, Sweden)*

"Non-linear behavior characterization methods for HFC networks return path devices and their relationship" *S. Bette, V. Moeyaert (Multitel a.s.b.l.)*

"Automatically Controlled Coverage of the Voltage Plane of Quasi-Unilateral Devices," *D. Schreurs, J. Wood, N. Tuffillaro, L. Barford, D.E. Root (ESAT-TELEMIC)*

"Use of Vectorial Large-Signal Measurements to Experimentally Evaluate Digital Circuits at Microwave Frequencies: Application to Inverters" *D Schreurs, E. Vandamme, (ESAT-TELEMIC)*

"Enhanced One-Port Noise Temperature Measurements Using a Noise Figure Meter" *M. Weatherspoon, L. Dunleavy (University of South Florida)*

"PAVO: A simple measurement based wideband nonlinear component model" *Y. Rolain, W. Van Moer, A. Geens (Vrije Universiteit Brussel)*

"A Straightforward De-embedding Method for Devices Embedded in Test Fixtures" *J.A. Reynoso-Hernandez, E. Inzunza-Gonzalez (CICISE, Ensenada, Mexico)*

"A Loopback GSM/DCS Bit Error Rate Test Method On Baseband IQ Outputs" *J.F. Nowakowski, B. Bonhoure, J-L Carbonero (STMicroelectronics)*

"Low Temperature Co-fired Ceramic LTCC Application Testing Alternative" *R. Stengel, L. Zhao (Motorola)*

"Characteristic Impedance Extraction Using Calibration Comparison," *S. Vandenberghe, D. Schreurs, G. Carchon, B. Nauwelaers, W. De Raedt, D. Vanhoenacker (TELEMIC)*

"Complex Relative Permittivity Measurement in the Frequency Range of 30-110 GHz by Fabry-Perot Resonator Method," *Ryuichi Katsumi (Japan Fine Ceramics Center)*